



<b>Searched</b>  	Application/Control No.  10052847	Applicant(s)/Patent Under Reexamination  YEUNG ET AL.
	Examiner Nawaz, Asad M	Art Unit 2155


Class	SubClass	Date	Examiner
709	202-207, 217-219, 223-238	10/1/06	AMN

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<b>Interference Searched</b>  	Application/Control No.  10052847	Applicant(s)/Patent Under Reexamination  YEUNG ET AL.
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Class	SubClass	Date	Examiner
709	225, 217,226,232	10/1/06	AMN

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<b>Search Notes</b>  	Application/Control No.	Applicant(s)/Patent Under Reexamination
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East Search (USPAT; USPGPUB; EPO; JPO; DERWENT; IBM_TDB)	10/1/06	AMN
Updated PgPub Search	10/1/06	AMN
Inventor Name Search for ODP	9/27/06	AMN
NPL Search (IEEE Xplore, ACM Digital Library)	9/27/06	AMN
Consulted Supervisory Examiner Saleh Najjar regarding allowability	9/26/06	AMN
Consulted Primary Examiner Phillip Tran regarding allowability	9/25/06	AMN
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